


<b>Search Notes</b>  	<b>Application/Control No.</b>  10581752	<b>Applicant(s)/Patent Under Reexamination</b>  DEORE ET AL.
	<b>Examiner</b>  SHANE FANG	<b>Art Unit</b>  1796

SEARCHED			
Class	Subclass	Date	Examiner
528	422	12/14/2009	sf

SEARCH NOTES		
Search Notes	Date	Examiner
NPL and STIC searched	12/14/2009	sf
search updated	8/9/2010	sf

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--